Searcn Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/088,468	NISHIO ET AL.	
Examiner	Art Unit	
Nhon T. Diep	2621	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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